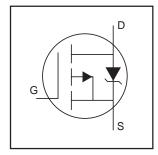
# International Rectifier

# IRFR/U5305

HEXFET® Power MOSFET

- Ultra Low On-Resistance
- Surface Mount (IRFR5305)
- Straight Lead (IRFU5305)
- Advanced Process Technology
- Fast Switching
- Fully Avalanche Rated

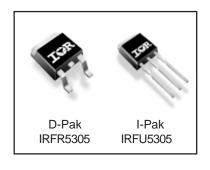


# $V_{DSS} = -55V$ $R_{DS(on)} = 0.065\Omega$ $I_{D} = -31A$

#### Description

Fifth Generation HEXFETs from International Rectifier utilize advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET® Power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.

The D-Pak is designed for surface mounting using vapor phase, infrared, or wave soldering techniques. The straight lead version (IRFU series) is for through-hole mounting applications. Power dissipation levels up to 1.5 watts are possible in typical surface mount applications.



#### **Absolute Maximum Ratings**

|   | Parameter  | Max.                   | Units |
|---|--|------------------------|-------|
| $I_D @ T_C = 25^{\circ}C$               | Continuous Drain Current, V <sub>GS</sub> @ -10V | -31                    |       |
| I <sub>D</sub> @ T <sub>C</sub> = 100°C | Continuous Drain Current, V <sub>GS</sub> @ -10V | -22                    | A     |
| I <sub>DM</sub>                         | Pulsed Drain Current ① ⑥                         | -110                   |       |
| P <sub>D</sub> @T <sub>C</sub> = 25°C   | Power Dissipation                                | 110                    | W     |
|   | Linear Derating Factor                           | 0.71                   | W/°C  |
| $V_{GS}$                                | Gate-to-Source Voltage                           | ± 20                   | V     |
| E <sub>AS</sub>                         | Single Pulse Avalanche Energy@6                  | 280                    | mJ    |
| I <sub>AR</sub>                         | Avalanche Current ① ⑥                            | -16                    | А     |
| E <sub>AR</sub>                         | Repetitive Avalanche Energy①                     | 11                     | mJ    |
| dv/dt                                   | Peak Diode Recovery dv/dt 3 6                    | -5.0                   | V/ns  |
| TJ                                      | Operating Junction and                           | -55 to + 175           |       |
| T <sub>STG</sub>                        | Storage Temperature Range                        |                        | ∞     |
|   | Soldering Temperature, for 10 seconds            | 300 (1.6mm from case ) |       |
|   | Mounting torque, 6-32 or M3 srew                 | 10 lbf•in (1.1N•m)     |       |

#### **Thermal Resistance**

|                 | Parameter                        | Тур. | Max. | Units |
|-----------------|----------------------------------|------|------|-------|
| $R_{\theta JC}$ | Junction-to-Case                 |      | 1.4  |       |
| $R_{\theta JA}$ | Junction-to-Ambient (PCB mount)* |      | 50   | °C/W  |
| $R_{\theta JA}$ | Junction-to-Ambient**            |      | 110  |       |

#### Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

|  | Parameter                            | Min. | Тур.   | Max.  | Units | Conditions  |
|--|--------------------------------------|------|--------|-------|-------|---|
| V <sub>(BR)DSS</sub>                   | Drain-to-Source Breakdown Voltage    | -55  |        |       | V     | $V_{GS} = 0V, I_D = -250\mu A$                      |
| ΔV <sub>(BR)DSS</sub> /ΔT <sub>J</sub> | Breakdown Voltage Temp. Coefficient  |      | -0.034 |       | V/°C  | Reference to 25°C, I <sub>D</sub> = -1mA            |
| R <sub>DS(on)</sub>                    | Static Drain-to-Source On-Resistance |      |        | 0.065 | Ω     | V <sub>GS</sub> = -10V, I <sub>D</sub> = -16A ④     |
| V <sub>GS(th)</sub>                    | Gate Threshold Voltage               | -2.0 |        | -4.0  | V     | $V_{DS} = V_{GS}, I_{D} = -250 \mu A$               |
| 9 <sub>fs</sub>                        | Forward Transconductance             | 8.0  |        |       | S     | V <sub>DS</sub> = -25V, I <sub>D</sub> = -16A©      |
|  | Drain-to-Source Leakage Current      |      |        | -25   | μA    | $V_{DS} = -55V, V_{GS} = 0V$                        |
| I <sub>DSS</sub>                       | Brain to Gource Leakage Guiterit     |      |        | -250  | μΑ    | $V_{DS} = -44V$ , $V_{GS} = 0V$ , $T_{J} = 150$ °C  |
| 1                                      | Gate-to-Source Forward Leakage       |      |        | 100   | nA    | V <sub>GS</sub> = 20V                               |
| I <sub>GSS</sub>                       | Gate-to-Source Reverse Leakage       |      |        | -100  | IIA   | V <sub>GS</sub> = -20V                              |
| Qg                                     | Total Gate Charge                    |      |        | 63    |       | I <sub>D</sub> = -16A                               |
| Q <sub>gs</sub>                        | Gate-to-Source Charge                |      |        | 13    | nC    | $V_{DS} = -44V$                                     |
| $Q_{gd}$                               | Gate-to-Drain ("Miller") Charge      |      |        | 29    |       | $V_{GS}$ = -10V, See Fig. 6 and 13 $\oplus$ $\odot$ |
| t <sub>d(on)</sub>                     | Turn-On Delay Time                   |      | 14     | _     |       | V <sub>DD</sub> = -28V                              |
| t <sub>r</sub>                         | Rise Time                            |      | 66     |       |       | $I_{D} = -16A$                                      |
| t <sub>d(off)</sub>                    | Turn-Off Delay Time                  |      | 39     | _     | ns    | $R_G = 6.8\Omega$                                   |
| t <sub>f</sub>                         | Fall Time                            |      | 63     |       |       | $R_D = 1.6\Omega$ , See Fig. 10 4 6                 |
|  | Internal Drain Inductance            |      | 4.5    |       |       | Between lead,                                       |
| L <sub>D</sub>                         | InternalDrainInductance              |      | 4.5    |       | nH    | 6mm (0.25in.)                                       |
| L <sub>S</sub>                         | Internal Source Inductance           |      | 7.5    |       | nH    | from package  |
|  |                                      |      |        |       |       | and center of die contact © s                       |
| C <sub>iss</sub>                       | Input Capacitance                    |      | 1200   | _     |       | $V_{GS} = 0V$                                       |
| C <sub>oss</sub>                       | Output Capacitance                   |      | 520    |       | рF    | $V_{DS} = -25V$                                     |
| C <sub>rss</sub>                       | Reverse Transfer Capacitance         |      | 250    |       |       | f = 1.0MHz, See Fig. 5 ®                            |

#### Source-Drain Ratings and Characteristics

|                 | Parameter                              | Min. | Тур. | Max. | Units | Conditions   |
|-----------------|--|------|------|------|-------|--|
| Is              | Continuous Source Current (Body Diode) |      |      | -31  |       | MOSFET symbol showing the                            |
| I <sub>SM</sub> | Pulsed Source Current (Body Diode) ①   |      |      | -110 | Α     | integral reverse p-n junction diode.                 |
| V <sub>SD</sub> | Diode Forward Voltage                  |      |      | -1.3 | V     | $T_J = 25^{\circ}C$ , $I_S = -16A$ , $V_{GS} = 0V$ ④ |
| t <sub>rr</sub> | Reverse Recovery Time                  |      | 71   | 110  | ns    | $T_J = 25^{\circ}C, I_F = -16A$                      |
| Q <sub>rr</sub> | Reverse Recovery Charge                |      | 170  | 250  | nC    | di/dt = -100A/μs ④ ⑥                                 |

#### Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See Fig. 11)
- ②  $V_{DD}$  = -25V, starting  $T_J$  = 25°C, L = 2.1mH  $R_G$  = 25 $\Omega$ ,  $I_{AS}$  = -16A. (See Figure 12)
- $\label{eq:loss} \begin{array}{l} \text{ } 3 \text{ } I_{SD} \leq \text{-16A, di/dt} \leq \text{-280A/}\mu\text{s, } V_{DD} \leq V_{(BR)DSS}, \\ T_{J} \leq 175 ^{\circ}\text{C} \end{array}$
- ⓐ Pulse width ≤ 300 $\mu$ s; duty cycle ≤ 2%.
- \$ This is applied for I-PAK, L<sub>S</sub> of D-PAK is measured between lead and center of die contact.
- © Uses IRF5305 data and test conditions.

For recommended footprint and soldering techniques refer to application note #AN-994.

<sup>\*</sup> When mounted on 1" square PCB (FR-4 or G-10 Material).

<sup>\*\*</sup> Uses typical socket mount.

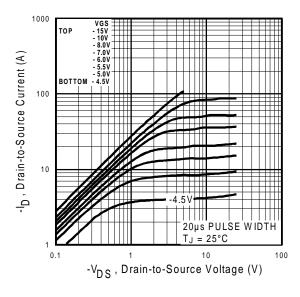


Fig 1. Typical Output Characteristics

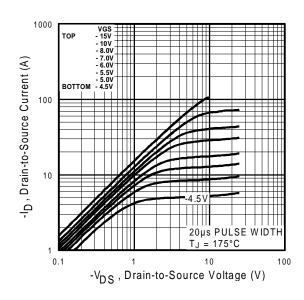


Fig 2. Typical Output Characteristics

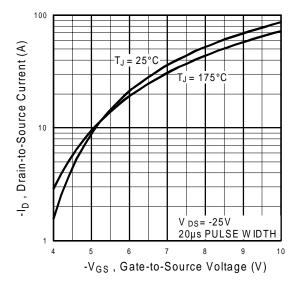
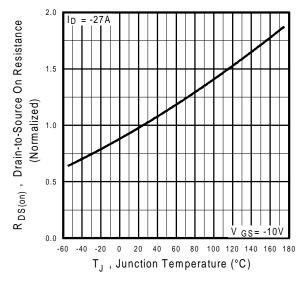
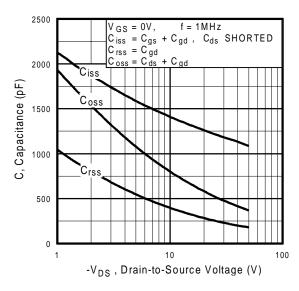


Fig 3. Typical Transfer Characteristics



**Fig 4.** Normalized On-Resistance Vs. Temperature



**Fig 5.** Typical Capacitance Vs. Drain-to-Source Voltage

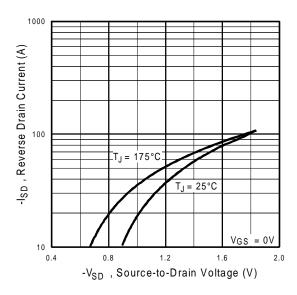
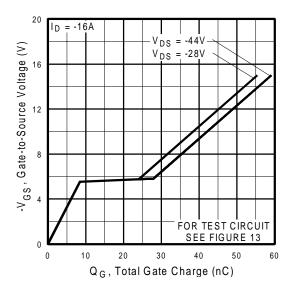


Fig 7. Typical Source-Drain Diode Forward Voltage



**Fig 6.** Typical Gate Charge Vs. Gate-to-Source Voltage

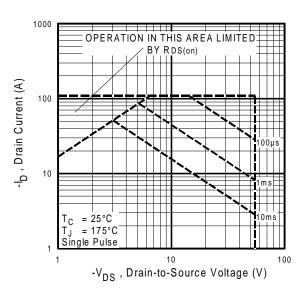
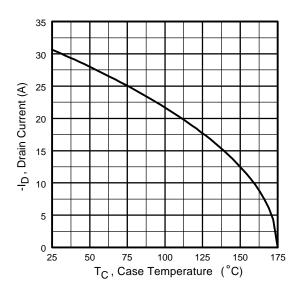


Fig 8. Maximum Safe Operating Area

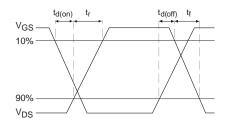
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# IRFR/U5305



 $\begin{array}{c|c} V_{DS} & & & \\ V_{GS} & & & \\ \hline V_{BS} & & & \\ \hline V_{DS} & & & \\ \hline V_{DD} & & & \\ V$ 

Fig 10a. Switching Time Test Circuit



**Fig 9.** Maximum Drain Current Vs. Case Temperature

Fig 10b. Switching Time Waveforms

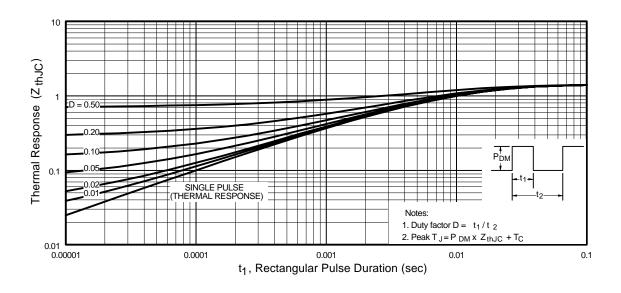


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

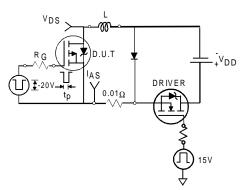


Fig 12a. Unclamped Inductive Test

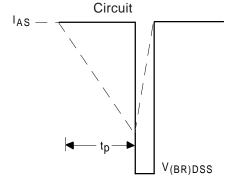


Fig 12b. Unclamped Inductive Waveforms

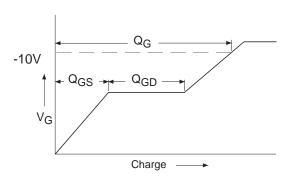
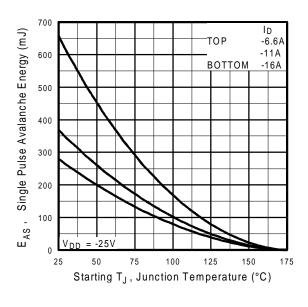


Fig 13a. Basic Gate Charge Waveform



**Fig 12c.** Maximum Avalanche Energy Vs. Drain Current

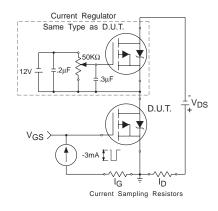
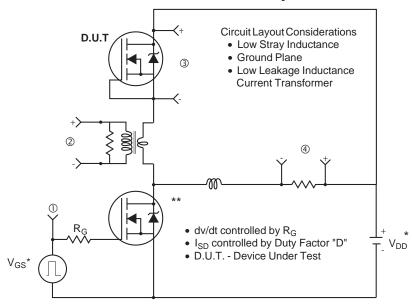


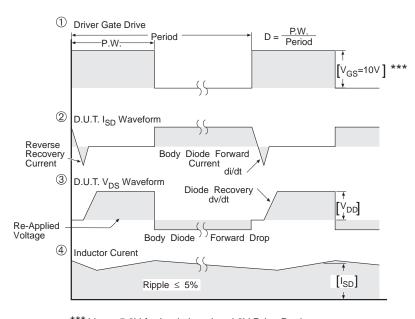
Fig 13b. Gate Charge Test Circuit

#### Peak Diode Recovery dv/dt Test Circuit



<sup>\*</sup> Reverse Polarity for P-Channel

<sup>\*\*</sup> Use P-Channel Driver for P-Channel Measurements



<sup>\*\*\*</sup> V<sub>GS</sub> = 5.0V for Logic Level and 3V Drive Devices

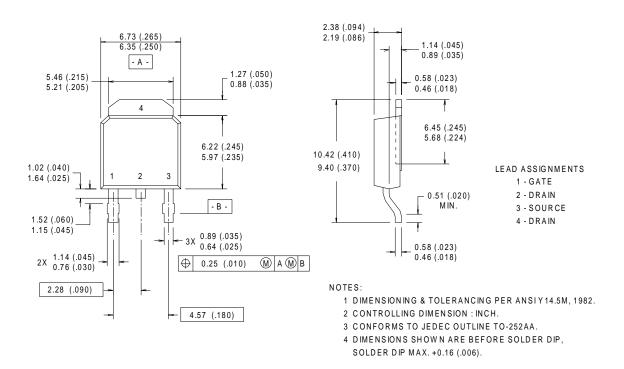
Fig 14. For P-Channel HEXFETS

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#### D-Pak (TO-252AA) Package Outline

Dimensions are shown in millimeters (inches)



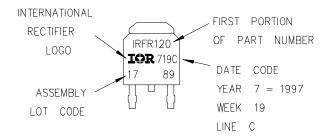
### D-Pak (TO-252AA) Part Marking Information

EXAMPLE: THIS IS AN IRFR120

LOT CODE 1789

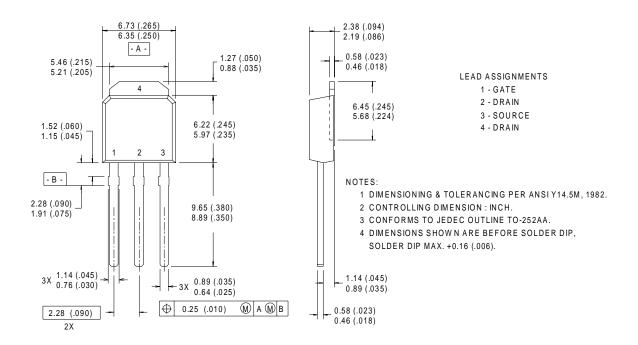
ASSEMBLED ON WW 19, 1997

IN THE ASSEMBLY LINE "C"



#### I-Pak (TO-251AA) Package Outline

Dimensions are shown in millimeters (inches)



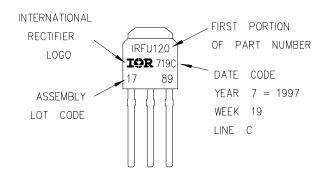
#### I-Pak (TO-251AA) Part Marking Information

EXAMPLE: THIS IS AN IRFU120

LOT CODE 1789

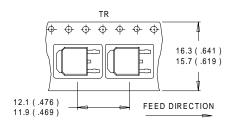
ASSEMBLED ON WW 19, 1997

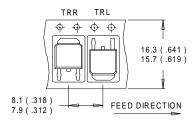
IN THE ASSEMBLY LINE "C"



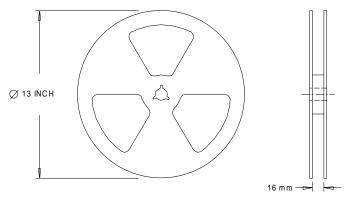
#### D-Pak (TO-252AA) Tape & Reel Information

Dimensions are shown in millimeters (inches)





- 1. CONTROLLING DIMENSION: MILLIMETER.
- 2. ALL DIMENSIONS ARE SHOWN IN MILLIMETERS (INCHES ). 3. OUTLINE CONFORMS TO EIA-481 & EIA-541.



1. OUTLINE CONFORMS TO EIA-481.

# International IOR Rectifier

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